

规格书编号

**SPEC NO:** 

# 产品规格书 SPECIFICATION

CUSTOMER 客户:							
PRODUCT 产品:	SAW FILTER						
MODEL NO 型 号:	HDF806ANF11						
PREPARED 编 制:	CHECKED 审 核	ξ̄:					
APPROVED 批 准:	DATE 日期	∃: 2006-5-11					
客户确认 CUSTOMER RECEIVED:							
审核 CHECKED	批准 APPROVED	日期 DATE					

# 无锡市好达电子有限公司 Shoulder Electronics Limited



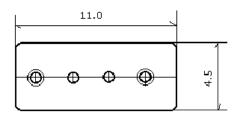
SAW FILTER HDF806ANF11

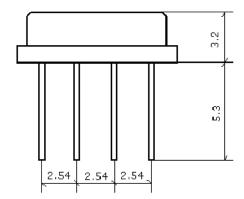
# 更改历史记录 History Record

更改日期 Date	规格书编号 Spec. No.	产品型号 Part No.	客户产品型号 Customer No.	更改内容描述 Modify Content	备注 Remark



# 1. Package Dimension





NO	Function	
1	Input	
2	Ground	
3	Ground	
4	Output	

Unit:mm

HDF806AN

## 2. Marking

2. Marking HD F806AN

2.1 Color: Black or Blue

2.2 806.: Center Frequency(MHz)

#### 3.Performance

3.1Application

Low-Loss SAW Filter of cordless system.

Center Frequency:806 MHz

3.2Maximum Rating

Operation Temperature Range	-40°C to +85°C	
Storage Temperature Range	-40°C to +85°C	
DC. Voltage	10 V max.	
Maximum Input Power	10dBm	

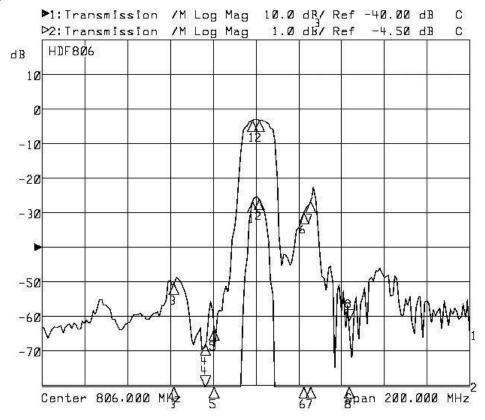


SAW FILTER HDF806ANF11

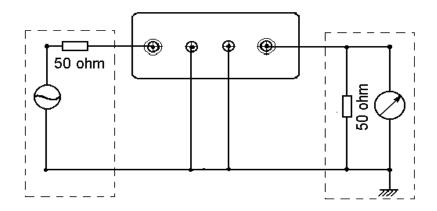
#### 3.3 Electronic Characteristics

Item	Frequency	Specification
Center Frequency(fo)	806MHz	
Pass Band Width	Fo±2MHz	
Insertion Loss	Passband	4.5dB max.
Stop Band Rejection	Fo-400~-40.8MHz	45dB min.
	Fo+50~+400MHz	45dB min.
Terminating Impedance		50 Ω

## 3.4 Frequency Characteristics



#### 3.5 Test Circuit





**SAW FILTER** 

## 4. ENVIRONMENTAL CHARACTERISTICS

#### 4-1 High temperature exposure

Subject the device to  $+85^{\circ}$ C for 16 hours. Then release the filter into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 3.3.

#### 4-2 Low temperature exposure

Subject the device to  $-40^{\circ}$ C for 16 hours. Then release the device into the room conditions for 24 hours prior to the measurement. It shall fulfill the specifications in 3.3.

#### 4-3 Temperature cycling

Subject the device to a low temperature of  $-40^{\circ}$ C for 30 minutes. Following by a high temperature of  $+85^{\circ}$ C for 30 Minutes. Then release the device into the room conditions for 24 hours prior to the measurement. It shall meet the specifications in 3.3.

#### 4-4 Resistance to solder heat

Dip the device terminals no closer than 1.5mm into the solder bath at  $260^{\circ}$ C  $\pm 10^{\circ}$ C for  $10\pm 1$  sec. Then release the device into the room conditions for 4 hours. The device shall meet the specifications in 3.3.

### 4-5 Solderability

Subject the device terminals into the solder bath at  $245^{\circ}$ C  $\pm 5^{\circ}$ C for 5s, More than 95% area of the terminals must be covered with new solder. It shall meet the specifications in 3.3.

#### 4-6 Mechanical shock

Drop the device randomly onto the concrete floor from the height of 1m 3 times. the device shall fulfill the specifications in 3.3.

#### 4-7 Vibration

Subject the device to the vibration for 1 hour each in x,y and z axes with the amplitude of 1.5 mm at 10 to 55 Hz. The device shall fulfill the specifications in 3.3.

#### 5. REMARK

#### 5.1 Static voltage

Static voltage between signal load & ground may cause deterioration &destruction of the component. Please avoid static voltage.

#### 5.2 Ultrasonic cleaning

Ultrasonic vibration may cause deterioration & destruction of the component. Please avoid ultrasonic cleaning

#### 5.3 Soldering

Only leads of component may be soldered. Please avoid soldering another part of component.